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U.S. UTILITY Patent Application

PATENT NUMBER and ISSUE DATE

APPL NUM	FILING DATE	1 .	SUBCLASS	GAU	EXAMINER
10084943	03/01/2002	438		2812	1 /
**APPLICAN		ami Kazuy	a; Suzuki Yuk	ihiro; Okut	ani Ken; Kajita Susumu
Hashimoto Ta	keshi;				
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	PLICATIONS VER	RIFIED:			
JAPAN 2001-57	974 03/02/2001				
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Verified and Actinowl	edged Examiners's intia	⊒ yes ⊒ ils		843	3.41231X00
FITLE: Method of manufacturing ap	f manufacturing se	miconduc	tor integrated	circuit devi	ce and semiconductor
	paratus			U.Ş	B.DEPT. OF COMM./PAT.& TM-PTO-436L(Rev. 12-94)
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ICE OF ALLOWA	NCE MAILED		102		CLAIMS ALLOWED

NOTICE OF ALLOWANCE MAILED ISSUE FEE			CLAIMS ALLOWED				
		Assistant Examiner			Print Claim for O.G		
			DRAWING				
Amount Due	Date Paid	7	Sheets Drwg.	Figs.Drwg.	Print Fig.		
TERMINAL		Primary Examiner		<u> </u>	<u> </u>		
		PREPARED FOR ISSUE	Application Examiner				
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